

General Description

The ICS854S1208I is a low skew, 8 output LVDS Fanout Buffer with selectable divider. The ICS854S1208I has 2 selectable inputs that accept a variety of differential input types. The device provides the capability to suppress any glitch at the outputs of the device during an input clock switch to enhance clock redundancy in fault tolerant applications.

The divide select inputs, DIV_SELA and DIV_SELB, control the output frequency of each bank. The output banks can be independently selected for ÷1 or ÷2 operation. The output enable pins assigned to each output, support enabling and disabling each output individually.

The ICS854S1208I is characterized at full 3.3V or 2.5V output operating supply modes. Guaranteed output and part-to-part skew characteristics make the ICS854S1208I ideal for high performance applications.

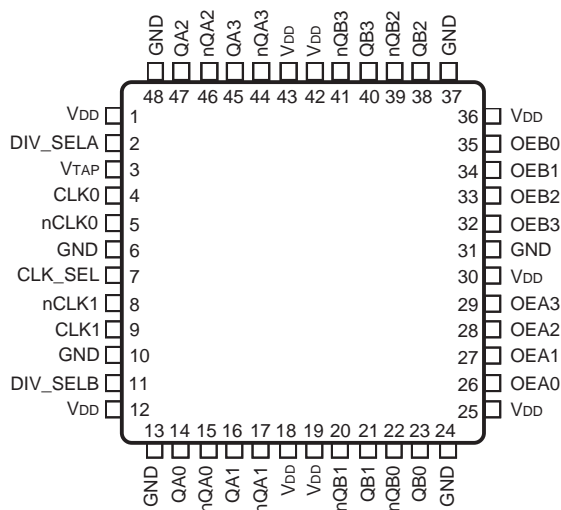
Features

- Eight differential LVDS output pairs
Each output has individual synchronous output enable
- Two selectable differential CLKx, nCLKx input pairs
- CLKx, nCLKx pairs can accept the following differential input levels: LVPECL, LVDS, HCSL
- Maximum output frequency: 1.5GHz
- Independent bank control for ÷1 or ÷2 operation
- Glitchless output behavior during input switch
- Output skew: 40ps (maximum)
- Bank skew: 35ps (maximum)
- Full 3.3V or 2.5V supply mode
- -40°C to 85°C ambient operating temperature
- Available in lead-free (RoHS 6) package

Supply Mode Operation Table

3.3V Operation	2.5V Operation
V _{DD} = 3.3V	V _{DD} = 2.5V
V _{TAP} = Float	V _{TAP} = 2.5V

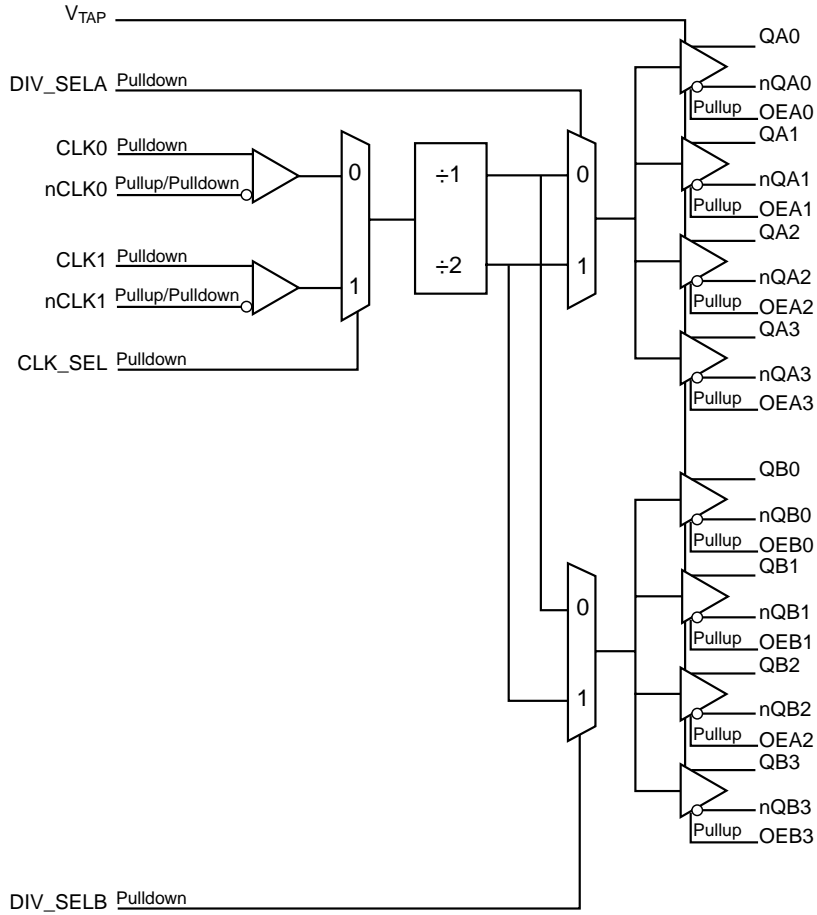
Pin Assignment



ICS854S1208I

48-Pin TQFP, E-Pad
7mm x 7mm x 1mm package body
Y Package
Top View

Block Diagram



Function Description

The ICS854S1208I has a glitch free input mux that is controlled by the CLK_SEL pin. It is designed to switch between 2 input clocks whether running or not. In the case where both clocks are running, when CLK_SEL changes, the output clocks go low after one cycle

of the output clock (nominally). The outputs then stay low for one cycle of the new input clock (nominally) and then begin to follow the new input clock. This is shown in *Figure 1A*.

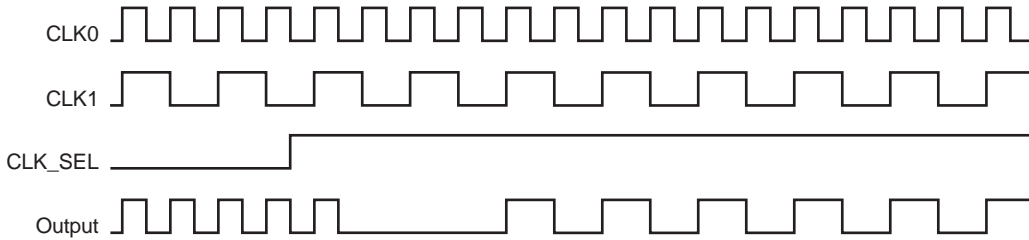


Figure 1A. CLK_SEL Timing Diagram

Another case is where one of the inputs was selected and running but has since stopped (either high or low). If a CLK_SEL event happens after a clock has stopped, the output change can take effect up to 1μs

after the input clock stopped. The output will go low and then follow the second period of the new clock input. Figure 1B shows an example of this.

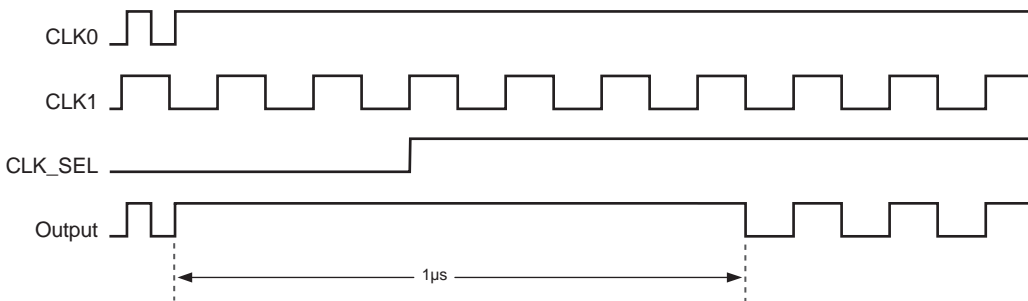


Figure 1B. CLK_SEL with Bad Input Timing Diagram

Table 1. Pin Descriptions

Number	Name	Type		Description
1, 12, 18, 19, 25, 30, 36, 42, 43	V _{DD}	Power		Power supply pins.
2	DIV_SELA	Input	Pulldown	Controls frequency division for QA[0:3], nQA[0:3] outputs. LVCMOS / LVTTTL interface levels.
3	V _{TAP}	Power		Power supply mode. See <i>Supply Mode Operation Table</i> on page 1.
4	CLK0	Input	Pulldown	Non-inverting differential clock input.
5	nCLK0	Input	Pullup/ Pulldown	Inverting differential clock input. V _{DD} /2 default when left floating.
6, 10, 13, 24, 31, 37, 48	GND	Power		Power supply ground.
7	CLK_SEL	Input	Pulldown	Clock select input. When HIGH, selects CLK1/nCLK1 inputs. When LOW, selects CLK0, nCLK0 inputs. LVCMOS / LVTTTL interface levels.
8	nCLK1	Input	Pullup/ Pulldown	Inverting differential clock input. V _{DD} /2 default when left floating.
9	CLK1	Input	Pulldown	Non-inverting differential clock input.
11	DIV_SELB	Input	Pulldown	Controls frequency division for QB[0:3], nQB[0:3] outputs. LVCMOS / LVTTTL interface levels.
14, 15	QA0, nQA0	Output		Differential output pair. LVDS interface levels.
16, 17	QA1, nQA1	Output		Differential output pair. LVDS interface levels.
20, 21	nQB1, QB1	Output		Differential output pair. LVDS interface levels.
22, 23	nQB0, QB0	Output		Differential output pair. LVDS interface levels.
26	OEA0	Input	Pullup	Output enable for QA0 output pair. LVCMOS/LVTTTL interface levels. See Table 3A.
27	OEA1	Input	Pullup	Output enable for QA1 output pair. LVCMOS/LVTTTL interface levels. See Table 3A.
28	OEA2	Input	Pullup	Output enable for QA2 output pair. LVCMOS/LVTTTL interface levels. See Table 3A.
29	OEA3	Input	Pullup	Output enable for QA3 output pair. LVCMOS/LVTTTL interface levels. See Table 3A.
32	OEB3	Input	Pullup	Output enable for QB3 output pair. LVCMOS/LVTTTL interface levels. See Table 3B.
33	OEB2	Input	Pullup	Output enable for QB2 output pair. LVCMOS/LVTTTL interface levels. See Table 3B.
34	OEB1	Input	Pullup	Output enable for QB1 output pair. LVCMOS/LVTTTL interface levels. See Table 3B.
35	OEB0	Input	Pullup	Output enable for QB0 output pair. LVCMOS/LVTTTL interface levels. See Table 3B.
38, 39	QB2, nQB2	Output		Differential output pair. LVDS interface levels.
40, 41	QB3, nQB3	Output		Differential output pair. LVDS interface levels.
44, 45	nQA3, QA3	Output		Differential output pair. LVDS interface levels.
46, 47	nQA2, QA2	Output		Differential output pair. LVDS interface levels.

NOTE: *Pullup and Pulldown* refer to internal input resistors. See Table 2, *Pin Characteristics*, for typical values.

Table 2. Pin Characteristics

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C _{IN}	Input Capacitance			2		pF
R _{PULLUP}	Input Pullup Resistor			51		kΩ
R _{PULLDOWN}	Input Pulldown Resistor			51		kΩ

Function Tables**Table 3A. OEAx Function Table**

Inputs	Outputs	
	QA[0:3]	nQA[0:3]
0	LOW	HIGH
1 (default)	Active	Active

Table 3B. OEBx Function Table

Inputs	Outputs	
	QB[0:3]	nQB[0:3]
0	LOW	HIGH
1 (default)	Active	Active

Table 3C. DIV_SELA Function Table

Input	Frequency Division
DIV_SELA	
0 (default)	÷1
1	÷2

Table 3D. DIV_SELB Function Table

Input	Frequency Division
DIV_SELB	
0 (default)	÷1
1	÷2

Table 3E. CLK_SEL Function Table

Input	Input Selection
CLK_SEL	
0 (default)	CLK0, nCLK0
1	CLK1, nCLK1

Absolute Maximum Ratings

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Item	Rating
Supply Voltage, V_{DD}	4.6V
Inputs, V_I	-0.5V to $V_{DD} + 0.5V$
Outputs, V_O	-0.5V to $V_{DD} + 0.5V$
Package Thermal Impedance, θ_{JA}	33.1°C/W (0 mps)
Storage Temperature, T_{STG}	-65°C to 150°C

DC Electrical Characteristics

Table 4A. Power Supply DC Characteristics, $V_{DD} = 3.3V \pm 5\%$, $T_A = -40^\circ C$ to $85^\circ C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{DD}	Positive Supply Voltage		3.135	3.3	3.465	V
V_{TAP}	Power Supply Mode		Float			V
I_{DD}	Power Supply Current				305	mA

Table 4B. Power Supply DC Characteristics, $V_{DD} = V_{TAP} = 2.5V \pm 5\%$, $T_A = -40^\circ C$ to $85^\circ C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{DD}	Positive Supply Voltage		2.375	2.5	2.625	V
V_{TAP}	Positive Supply Voltage		2.375	2.5	2.625	V
I_{DD}	Power Supply Current				290	mA
I_{TAP}	Power Supply Current				2.2	mA

Table 4C. LVCMOS/LVTTL DC Characteristics, $V_{DD} = 3.3V \pm 5\%$ or $V_{DD} = V_{TAP} = 2.5V \pm 5\%$, $T_A = -40^\circ C$ to $85^\circ C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{IH}	Input High Voltage	$V_{DD} = 3.465V$	2.2		$V_{DD} + 0.3$	V
		$V_{DD} = 2.625V$	1.7		$V_{DD} + 0.3$	V
V_{IL}	Input Low Voltage	$V_{DD} = 3.465V$	-0.3		0.8	V
		$V_{DD} = 2.625V$	-0.3		0.7	V
I_{IH}	Input High Current	DIV_SELx, CLK_SEL $V_{DD} = V_{IN} = 3.465V$ or $2.625V$			150	μA
		OEA[3:0], OEB[3:0] $V_{DD} = V_{IN} = 3.465V$ or $2.625V$			10	μA
I_{IL}	Input Low Current	DIV_SELx, CLK_SEL $V_{DD} = 3.465V$ or $2.625V$, $V_{IN} = 0V$	-10			μA
		OEA[3:0], OEB[3:0] $V_{DD} = 3.465V$ or $2.625V$, $V_{IN} = 0V$	-150			μA

Table 4D. Differential DC Characteristics, $V_{DD} = 3.3V \pm 5\%$ or $V_{DD} = V_{TAP} = 2.5V \pm 5\%$, $T_A = -40^\circ\text{C}$ to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
I_{IH}	Input High Current	CLK0, CLK1, nCLK0, nCLK1	$V_{DD} = V_{IN} = 3.465V$ or $2.625V$		150	μA
I_{IL}	Input Low Current	CLK0, CLK1	$V_{DD} = 3.465V$ or $2.625V$, $V_{IN} = 0V$	-10		μA
		nCLK0, nCLK1	$V_{DD} = 3.465V$ or $2.625V$, $V_{IN} = 0V$	-150		μA
V_{PP}	Peak-to-Peak Voltage; NOTE 1		0.15		1.3	V
V_{CMR}	Common Mode Input Voltage; NOTE 1, 2		GND + 0.5		$V_{DD} - 0.85$	V

NOTE 1: V_{IL} should not be less than $-0.3V$.NOTE 2: Common mode input voltage is defined as V_{IH} .**Table 4E. LVDS DC Characteristics, $V_{DD} = 3.3V \pm 5\%$, $T_A = -40^\circ\text{C}$ to 85°C**

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{OD}	Differential Output Voltage		247		454	mV
ΔV_{OD}	V_{OD} Magnitude Change				50	mV
V_{OS}	Offset Voltage		1.2		1.47	V
ΔV_{OS}	V_{OS} Magnitude Change				50	mV

Table 4F. LVDS DC Characteristics, $V_{DD} = V_{TAP} = 2.5V \pm 5\%$, $T_A = -40^\circ\text{C}$ to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{OD}	Differential Output Voltage		247		454	mV
ΔV_{OD}	V_{OD} Magnitude Change				50	mV
V_{OS}	Offset Voltage		1.15		1.45	V
ΔV_{OS}	V_{OS} Magnitude Change				50	mV

AC Electrical Characteristics

Table 5A. AC Characteristics, $V_{DD} = 3.3V \pm 5\%$, $T_A = -40^\circ\text{C}$ to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
f_{OUT}	Output Frequency				1.5	GHz
t_{PD}	Propagation Delay; NOTE 1		0.7		1.75	ns
$t_{sk(o)}$	Output Skew; NOTE 2, 3				40	ps
$t_{sk(pp)}$	Part-to-Part Skew; NOTE 3, 4				400	ps
$t_{sk(b)}$	Bank Skew; NOTE 3, 5				35	ps
t_R / t_F	Output Rise/Fall Time	20% to 80%	55		250	ps
odc	Output Duty Cycle	$f \leq 750\text{MHz}$	44		56	%
t_{EN}	Output Enable Time; NOTE 6				10	ns
t_{DIS}	Output Disable Time; NOTE 6				10	ns

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lpm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

NOTE 1: Measured from the differential input crossing point to the differential cross points.

NOTE 2: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at the differential cross points.

NOTE 3: These parameters are guaranteed by characterization. Not tested in production.

NOTE 4: Defined as skew between outputs on different devices operating at the same supply voltage, same temperature and with equal load conditions. Using the same type of input on each device, the output is measured at the differential cross points.

NOTE 5: Defined as skew within a bank of outputs at the same supply voltage and with equal load conditions.

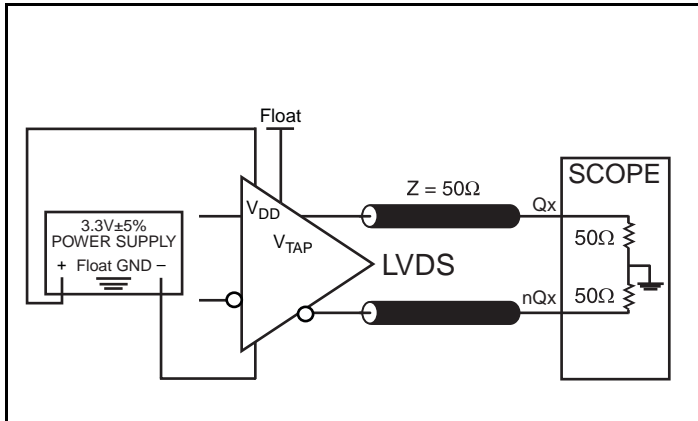
NOTE 6: These parameters are guaranteed by characterization. Not tested in production.

Table 5B. AC Characteristics, $V_{DD} = V_{TAP} = 2.5V \pm 5\%$, $T_A = -40^\circ\text{C}$ to 85°C

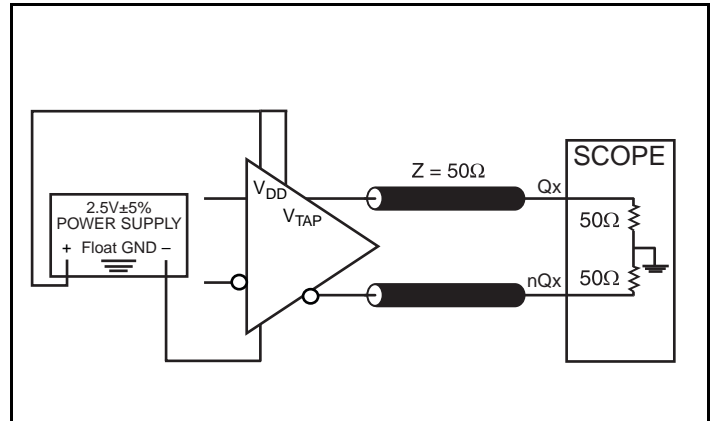
Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
f_{OUT}	Output Frequency				1.5	GHz
t_{PD}	Propagation Delay; NOTE 1		0.6		1.8	ns
$t_{sk(o)}$	Output Skew; NOTE 2, 3				40	ps
$t_{sk(pp)}$	Part-to-Part Skew; NOTE 3, 4				400	ps
$t_{sk(b)}$	Bank Skew; NOTE 3, 5				35	ps
t_R / t_F	Output Rise/Fall Time	20% to 80%	50		275	ps
odc	Output Duty Cycle	$f \leq 750\text{MHz}$	44		56	%
t_{EN}	Output Enable Time; NOTE 6				10	ns
t_{DIS}	Output Disable Time; NOTE 6				10	ns

For NOTES, see Table 5A above.

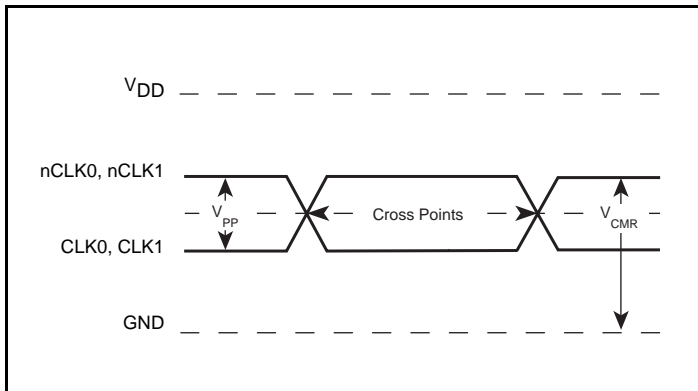
Parameter Measurement Information



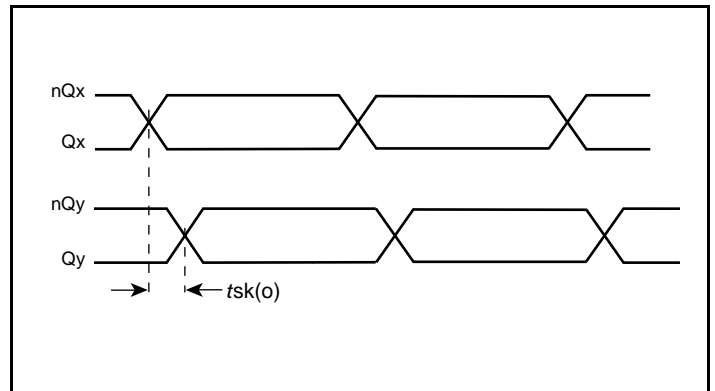
3.3V LVDS Output Load AC Test Circuit



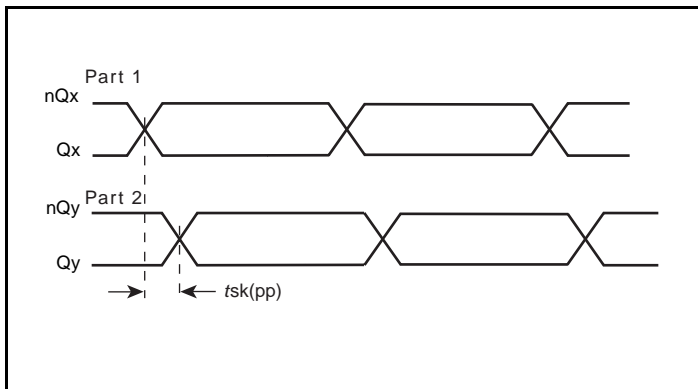
2.5V LVDS Output Load AC Test Circuit



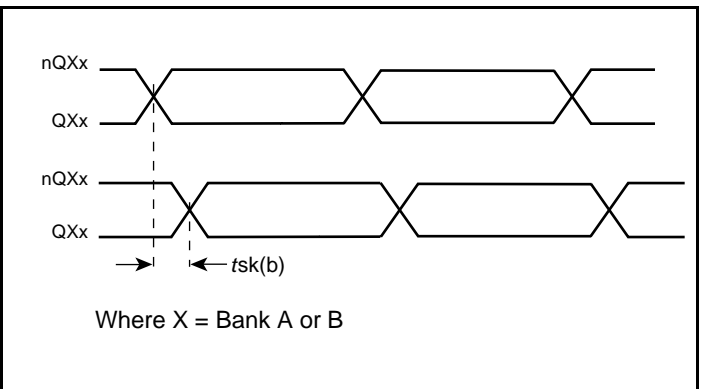
Differential Input Level



Output Skew

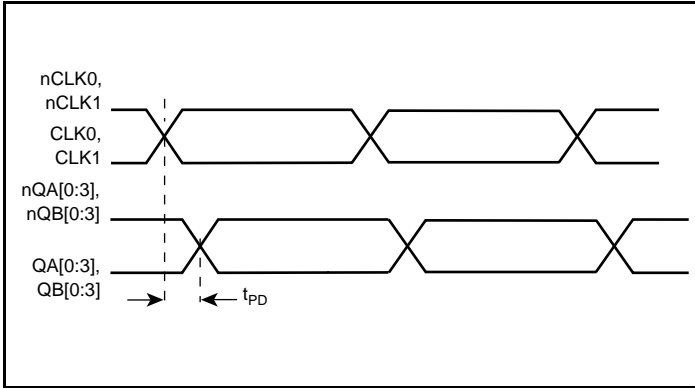


Part-to-Part Skew

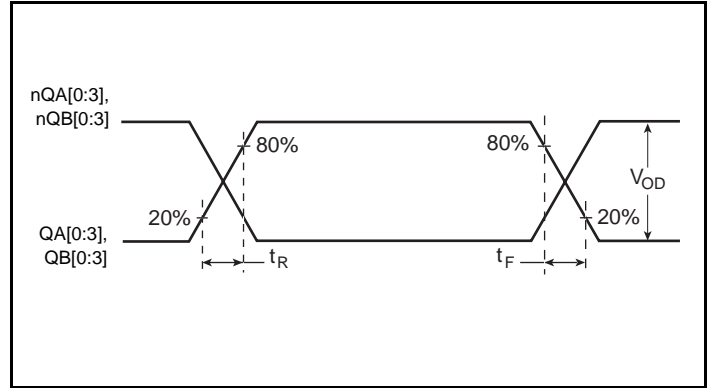


Bank Skew

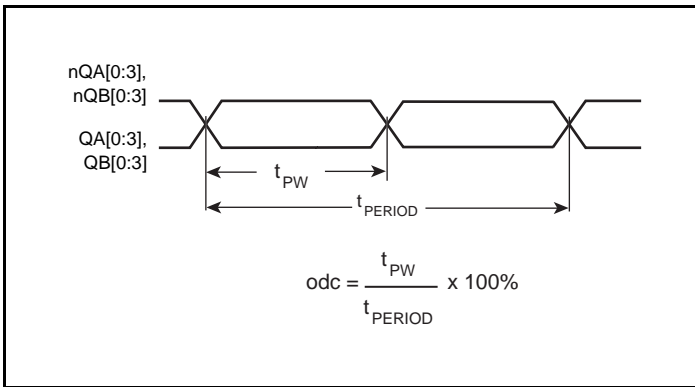
Parameter Measurement Information, continued



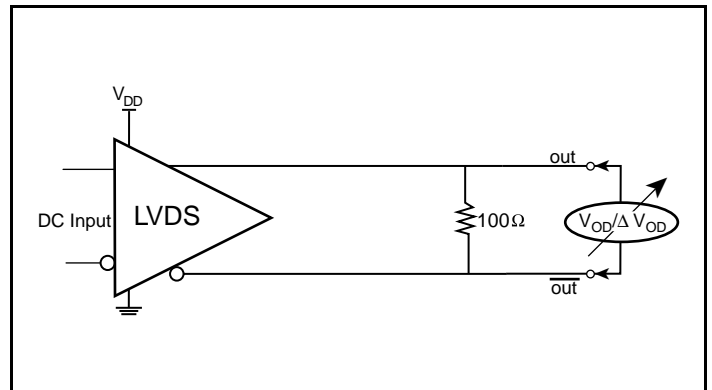
Propagation Delay



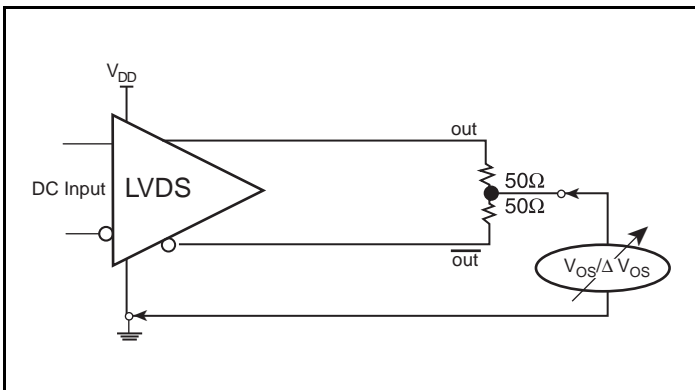
Output Rise/Fall Time



Output Duty Cycle/Pulse Width/Period



Differential Output Voltage Setup

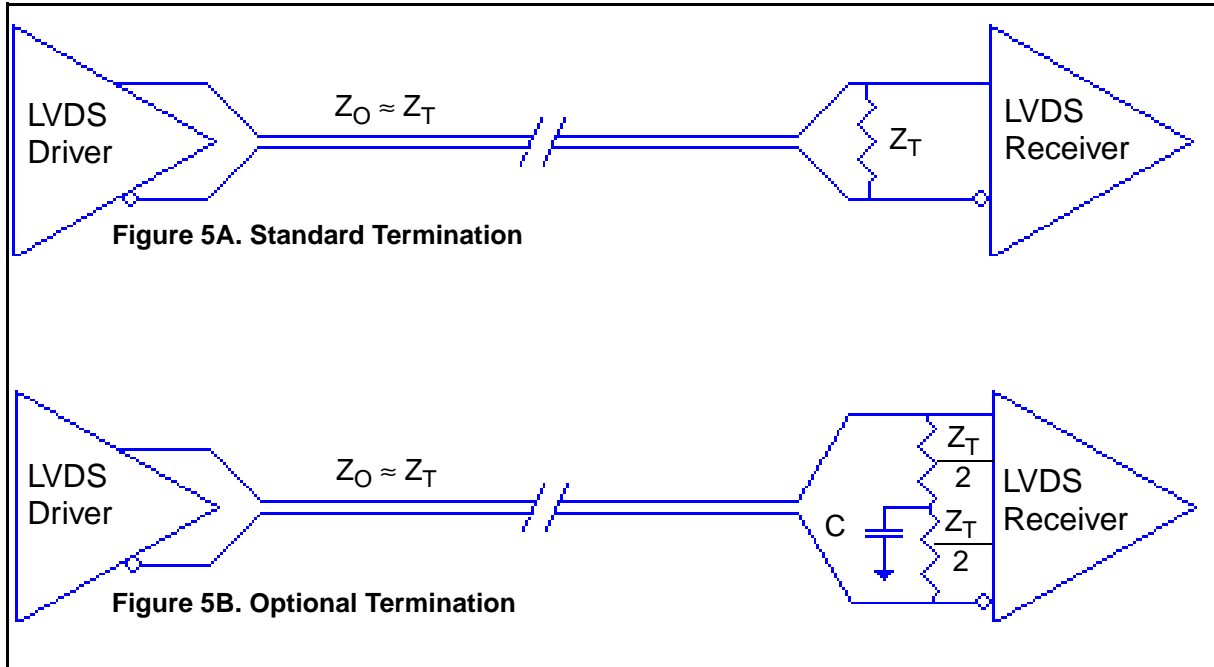


Offset Voltage Setup

LVDS Driver Termination

A general LVDS interface is shown in *Figure 5A*. Standard termination for LVDS type output structure requires both a 100Ω parallel resistor at the receiver and a 100Ω differential transmission line environment. In order to avoid any transmission line reflection issues, the 100Ω resistor must be placed as close to the receiver as possible. IDT offers a full line of LVDS compliant devices with two types of output structures: current source and voltage source. The

standard termination schematic as shown in *Figure 5A* can be used with either type of output structure. If using a non-standard termination, it is recommended to contact IDT and confirm if the output is a current source or a voltage source type structure. In addition, since these outputs are LVDS compatible, the amplitude and common mode input range of the input receivers should be verified for compatibility with the output.



LVDS Driver Termination

LVDS Power Considerations

This section provides information on power dissipation and junction temperature for the ICS854S1208I. Equations and example calculations are also provided.

1. Power Dissipation.

The total power dissipation for the ICS854S1208I is the sum of the core power plus the power dissipated in the load(s). The following is the power dissipation for $V_{DD} = 3.3V + 5\% = 3.465V$, which gives worst case results.

Max power dissipation occurs at $-40^{\circ}C$.

Max I_{DD} at $-40^{\circ}C = 305mA$

- $Power_{MAX} = V_{DD_MAX} * I_{DD_MAX} = 3.465V * 305mA = \mathbf{1056.825mW}$

2. Junction Temperature.

Junction temperature, T_j , is the temperature at the junction of the bond wire and bond pad directly affects the reliability of the device. The maximum recommended junction temperature is $125^{\circ}C$. Limiting the internal transistor junction temperature, T_j , to $125^{\circ}C$ ensures that the bond wire and bond pad temperature remains below $125^{\circ}C$.

The equation for T_j is as follows: $T_j = \theta_{JA} * Pd_total + T_A$

T_j = Junction Temperature

θ_{JA} = Junction-to-Ambient Thermal Resistance

Pd_total = Total Device Power Dissipation (example calculation is in section 1 above)

T_A = Ambient Temperature

In order to calculate junction temperature, the appropriate junction-to-ambient thermal resistance θ_{JA} must be used. Assuming no air flow and a multi-layer board, the appropriate value is $33.1^{\circ}C/W$ per Table 6 below.

Max I_{DD} at $85^{\circ}C = 287.8mA$.

Max power at $85^{\circ}C = 3.465V * 287.8mA = 997.227mW$.

Therefore, T_j for an ambient temperature of $85^{\circ}C$ with all outputs switching is:

$$85^{\circ}C + 0.997W * 33.1^{\circ}C/W = 118^{\circ}C. \text{ This is below the limit of } 125^{\circ}C.$$

This calculation is only an example. T_j will obviously vary depending on the number of loaded outputs, supply voltage, air flow and the type of board (multi-layer).

Table 6. Thermal Resistance θ_{JA} for 48 Lead TQFP, E-Pad, Forced Convection

θ_{JA} by Velocity			
Meters per Second	0	1	2.5
Multi-Layer PCB, JEDEC Standard Test Boards	$33.1^{\circ}C/W$	$27.2^{\circ}C/W$	$25.7^{\circ}C/W$

Reliability Information

Table 7. θ_{JA} vs. Air Flow Table for a 48 Lead TQFP, E-Pad

θ_{JA} vs. Air Flow			
Meters per Second	0	1	2.5
Multi-Layer PCB, JEDEC Standard Test Boards	33.1°C/W	27.2°C/W	25.7°C/W

Transistor Count

The transistor count for ICS854S1208I is: 9878

Package Outline and Package Dimensions

Package Outline - Y Suffix for 48 Lead TQFP, E-Pad

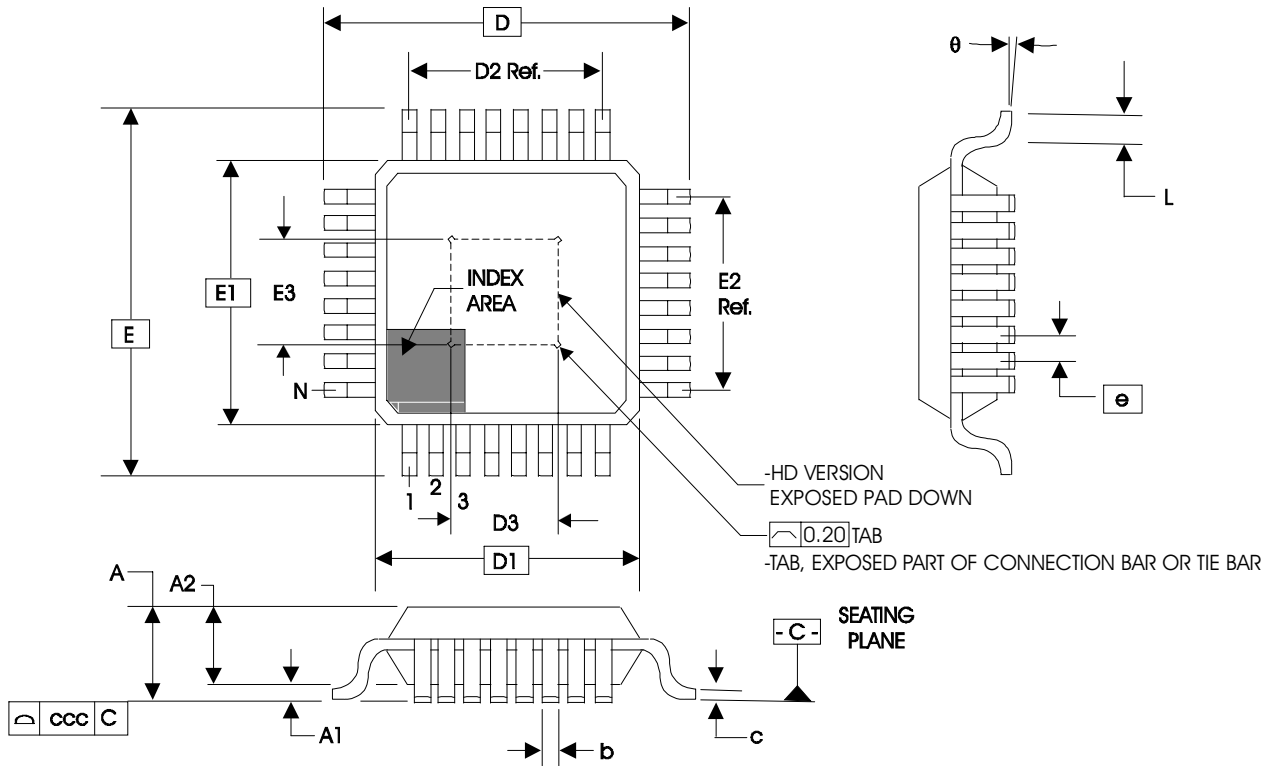


Table 8. Package Dimensions for 48 Lead TQFP, E-Pad

JEDEC Variation: BBC - HD			
All Dimensions in Millimeters			
Symbol	Minimum	Nominal	Maximum
N		48	
A			1.20
A1	0.05	0.10	0.15
A2	0.95	1.00	1.05
b	0.17	0.22	0.27
c	0.09		0.20
D & E		9.00 Basic	
D1 & E1		7.00 Basic	
D2 & E2		5.50 Ref.	
D3 & E3		3.5	
e		0.5 Basic	
L	0.45	0.60	0.75
ccc			0.08
θ	0°		7°

Reference Document: JEDEC Publication 95, MS-026

Ordering Information

Table 9. Ordering Information

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
854S1208AYILF	ICS4S1208AIL	"Lead-Free" 48 Lead TQFP, E-Pad	Tray	-40°C to 85°C
854S1208AYILFT	ICS4S1208AIL	"Lead-Free" 48 Lead TQFP, E-Pad	1000 Tape & Reel	-40°C to 85°C

NOTE: Parts that are ordered with an "LF" suffix to the part number are the Pb-Free configuration and are RoHS compliant.

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